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(54) Title: RESISTANCE MEASUREMENT SYSTEM AND METHOD OF USING THE SAME

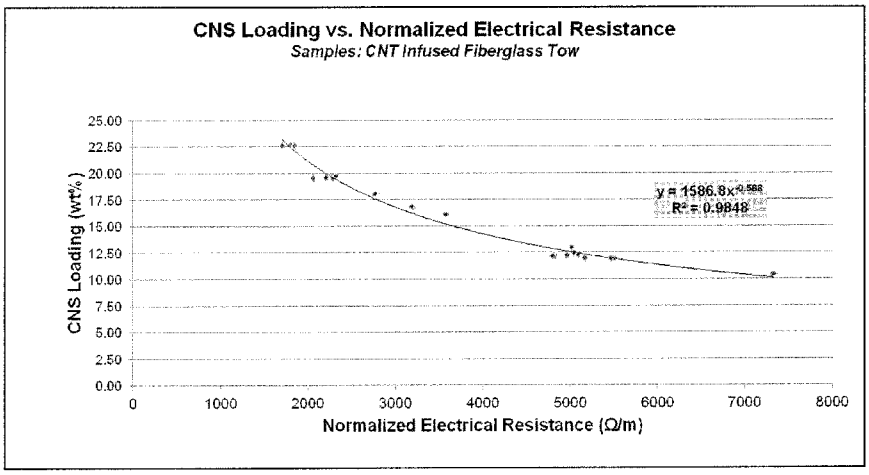

Figure 1

(57) Abstract: A quality control system for the manufacture of carbon nanostructure-laden substrates includes a resistance measurement module for continuously measuring resistance of the carbon nanostructure (CNS)-laden substrate.

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INTERNATIONAL SEARCH REPORT

International application No.
PCT/US 13/29196

A. CLASSIFICATION OF SUBJECT MATTER
IPC(8) - G01N 19/00 (2013.01)
USPC - 73/335.05
According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC(8) - G01N 19/00 (2013.01)
USPC - 73/335.05

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched
USPC: 73/204.25;977/953,742 (search terms- See below)

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)
PatBase and Google. Search terms: quality, test, standard, carbon, nanotube, nanostructure, substrate, support, continuous, ongoing, measure, monitor, resist, conduct, resistivity, support, fiber, ribbon, tape, mesh, electric, field, inductance, capacitance, feedback, feed, back, process, control, pressure, temperature, gas, beltspeed, linespeed, d

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	US 2011/0089958 A1 (Malecki et al.) 21 April 2011 (21.04.2011) Entire document, especially para [0004], [0033], [0034], [0035], [0040], [0056], [0078], [0100]-[0109] X 1, 3 LOIS 10, 13-19	1, 3, 10 and 12-19
Y		2, 4-9 and 11
Y	US 5,891,306 A (Chase et al.) 06 April 1999 (06.04.1999) Entire document, especially cl 14 and col 2, ln 14-18; col 2, ln 66 to col 3, ln 10	2, 4-9
Y	US 2005/0150620 A1 (Hamada et al.) 14 July 2005 (14.07.2005) Entire document, especially para [0064]).	11

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